

	Application/Control No.	Applicant(s)/Pate Reexamination	nt(s)/Patent under nination	
	10/038,943	NALLUR ET AL	•	
Γ	Examiner	Art Unit		
	Daniel Tekle	2621		

	SEAR	CHED	
Class	Subclass	Date	Examiner
386	68	8/1/2006	DT
386	46	8/1/2006	DT
386	86	8/1/2006	DT

TMI	TERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East data base (I or B or P) adj3 (frame\$1 or picture\$1) same (trick or fast or high) near3 (speed or reproduc\$4) same (memor	8/3/2006	DT
NPL (ACM digital library) PLUS Inventer search	8/1/2006	dt
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	8/1/2006	DT
Boccio Vincent	8/3/2006	DT